

# *Trapped Ion Experiments at Sandia National Laboratories Waterloo 2018*



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# AMO Physics at Sandia

## Trapped Ions:

- Surface trap fabrication
- Ion shuttling and reordering
- Characterization of high fidelity quantum gates with Gate Set Tomography (GST)

Ion Clocks

## Neutral Atoms:

- Two-qubit gates
- Atom interferometry

## Solid State (AMO-like):

- Phosphorous donors in Silicon
- Quantum Dots
- CINT

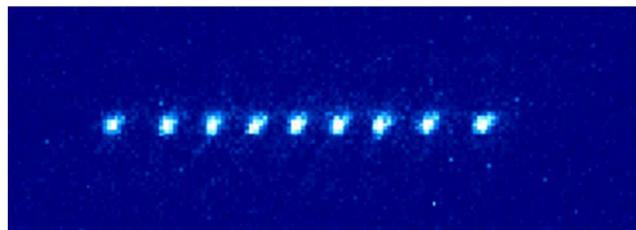
# Uses of Trapped Ions

**Mass Spectrometry:** Identify substances by mass to charge ratio

Isotope dating and tracking, Trace gas analysis, protein characterization, space exploration (mars rover), antiproton storage at CERN, drinking water safety...

**Precision clocks:** Narrow transitions allow for accurate time standards

**Quantum information:** Electron spin for simulation and memory



# Ions for Quantum Information

**Quantum Experimental Platforms answer questions about:**

- 1) The nature of information
- 2) Fundamentals of quantum mechanics
- 3) Secure information transfer
- 4) Simulating more complicated systems
- 5) New types of computing resources for certain problems

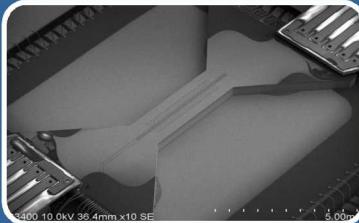
**Main Advantages of Ions:**

Well understood and mature system

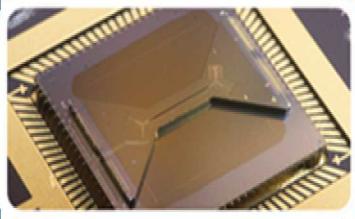
Main sources of error are classical control problems

(microwaves/lasers/electric field noise/varying magnetic fields)

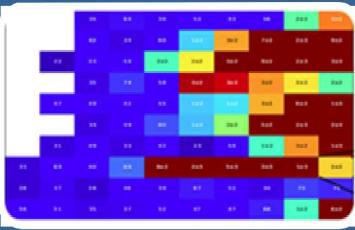
# Outline



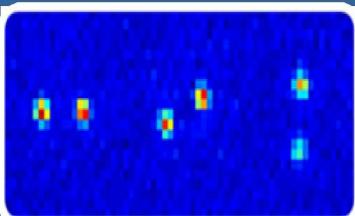
Trap fabrication, advantages and challenges



Example trap designs: High Optical Access trap & Microwave trap



Characterization of quantum gates using Gate Set Tomography (GST)



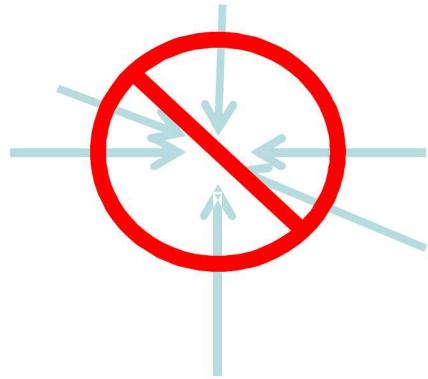
Recent Results in Surface Traps: Ion shuttling, high fidelity operations, sympathetic cooling

# Earnshaw's Theorem and Ion Trapping

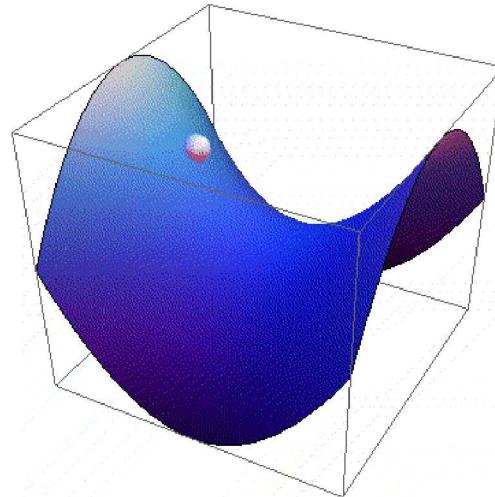
Trapping requirement: A restoring force when displaced from trap center (in any direction)

Cannot use static electric fields to trap a charge

Field lines cannot cross, and must start/end on sources/drains

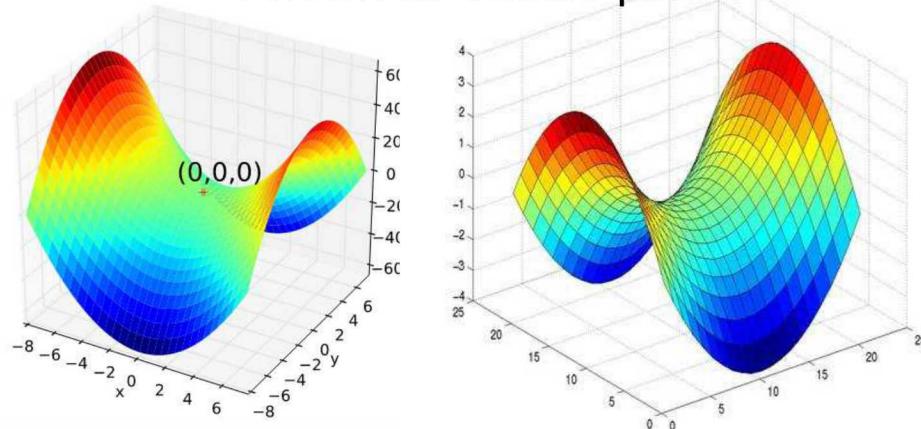


Before ion escapes, field reverses!



Courtesy of Wes Campbell

Known as saddle points

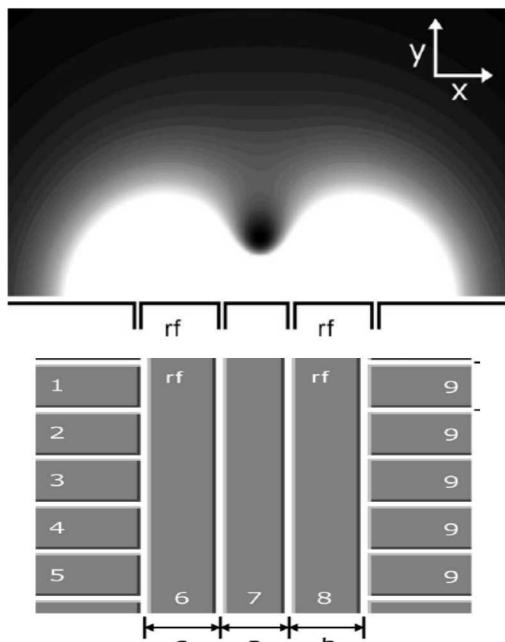


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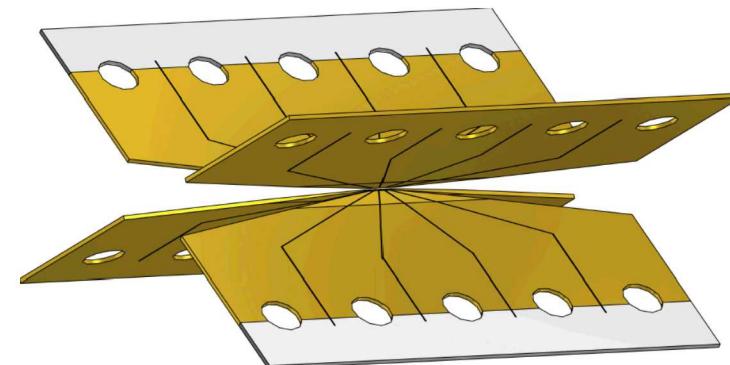
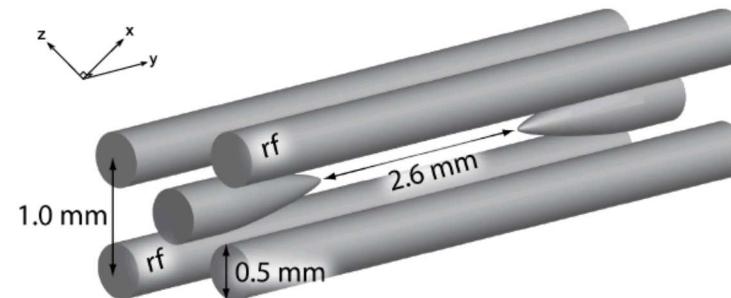
# Various trap geometries

Use a combination of static and rf fields to trap ions  
Various geometries possible

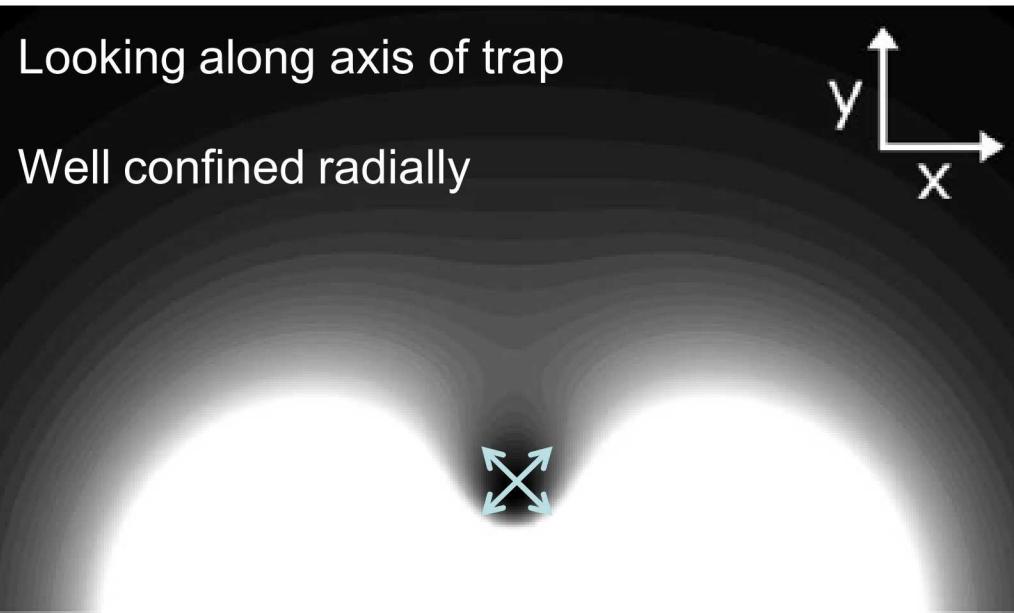
Pseudopotential well (dark area) formed along the axis of a surface trap



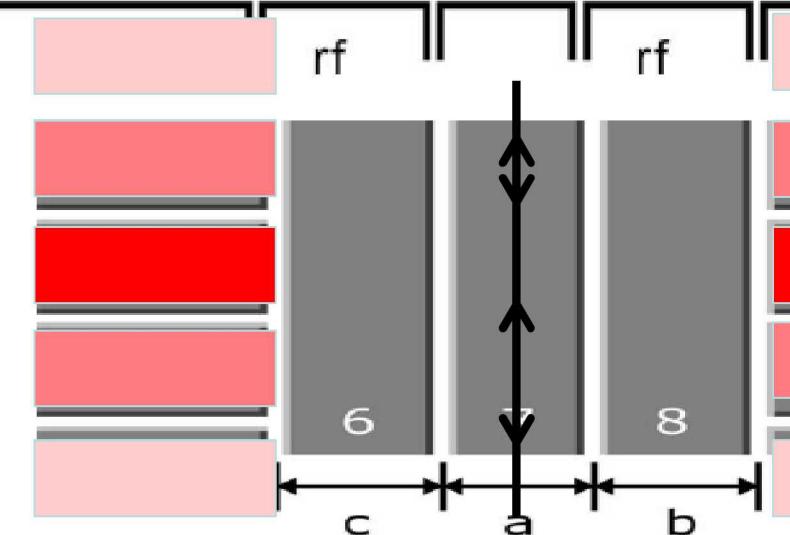
Electrodes from above



# Need for DC fields



Looking at trap  
from above



Still free to  
move along  
axis

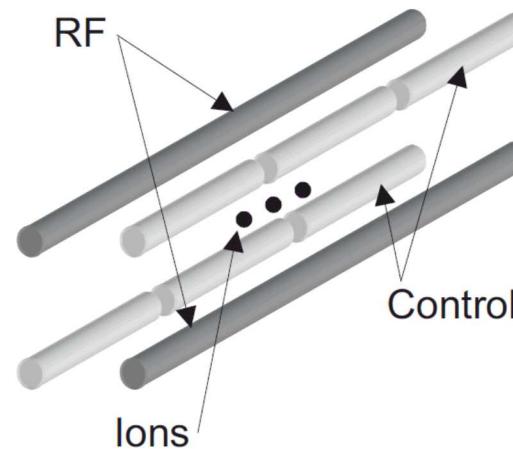
Use DC fields on  
the electrodes to  
confine

Creates a trapping  
potential along  
axis

# Advantages/Challenges vs 3D

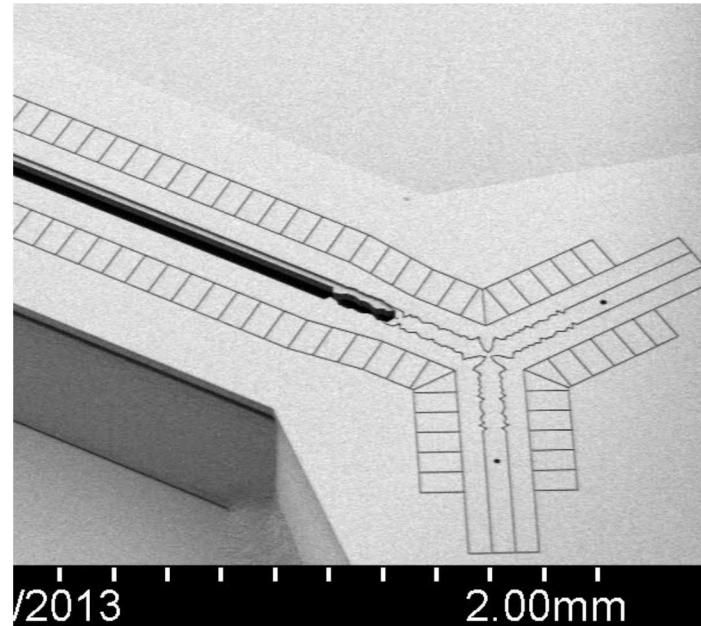
## Advantages

- Greater field control (more electrodes)
- Flexible, precise 2D geometry
- More manufacturable
- Consistent geometry → consistent behavior
- Laser access
- Integration of other technologies (waveguides, detectors, filters...)



## Challenges

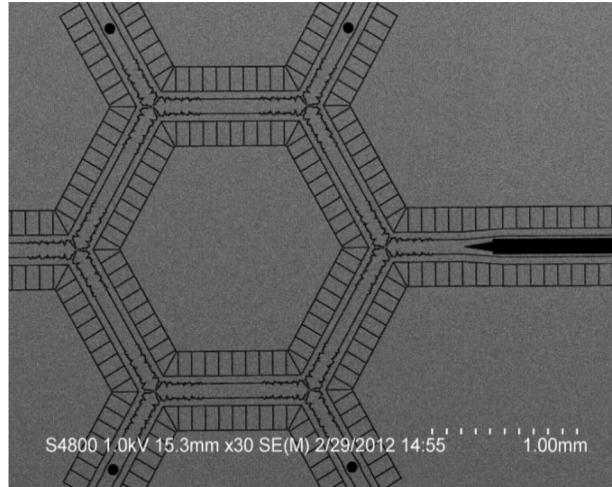
- Lower depth (ion lifetime), anharmonicities in potential
- Proximity to surface (charging, heating)
- Delicate (dust, voltage)
- Capacitance
- Laser access



# Capabilities & Requirements

## Essential capabilities

- Reliable and consistent operation
- Store ions for long periods of time (hours)
- Move ions to achieve 2D connectivity
- Support high fidelity operations



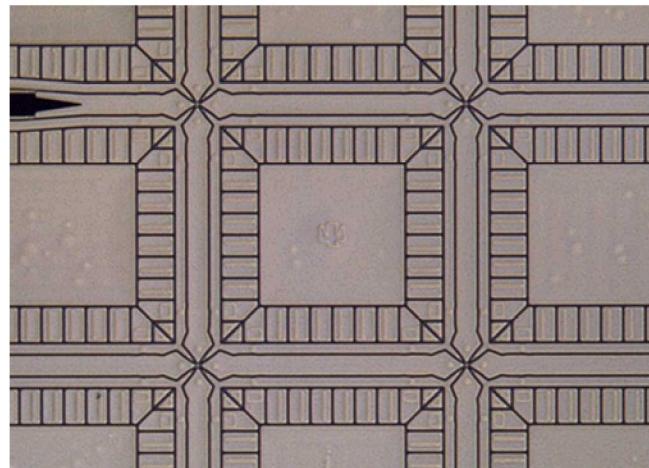
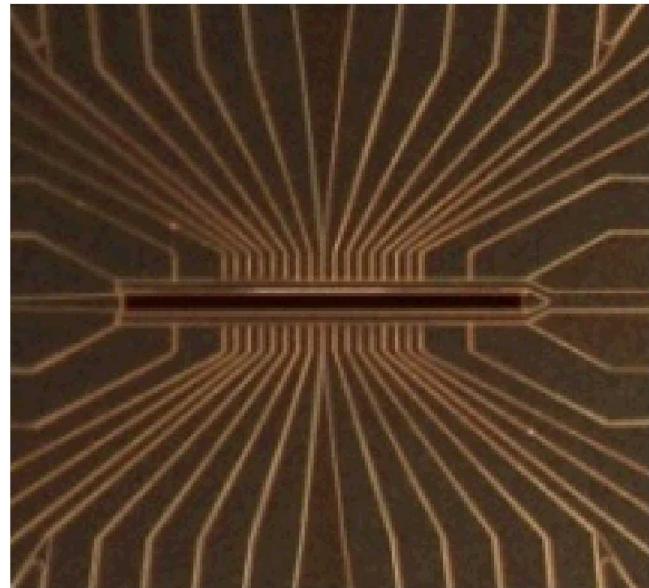
## MESA facility

- Radiation hardened CMOS
- Leverages reliability of NW processing
- Large feature sizes (350 nm) match well with trap requirements

# Capabilities & Requirements

## Derived requirements

- Standardization (lithographically defined electrodes)
- Multi-unit production
- Multi-level lead routing for accessing interior electrodes
  - Connecting both control and RF electrodes
  - Any 2D topology is possible
- Voltage breakdown  $>300$  V @  $\sim 50$  MHz
- Overhung electrodes
- Low electric field noise (heating)
- Backside loading holes
- Trench capacitors
- High optical access (delivery and collection)

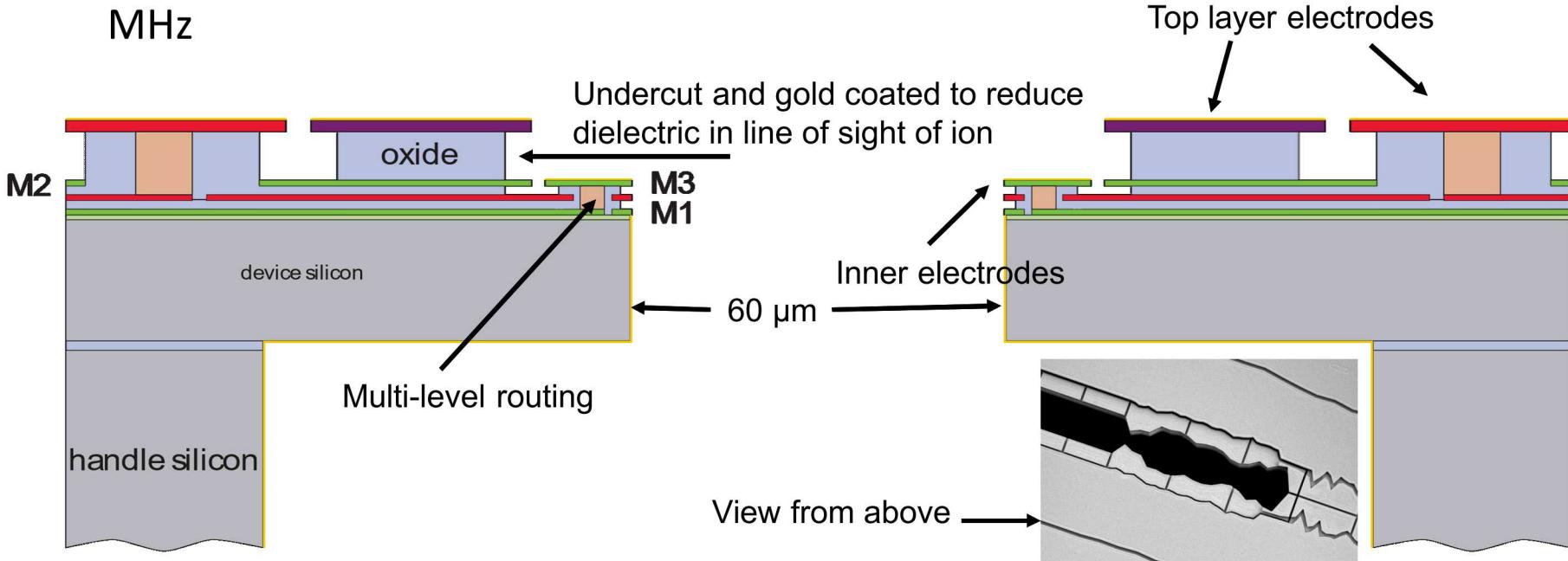


# Capabilities & Requirements

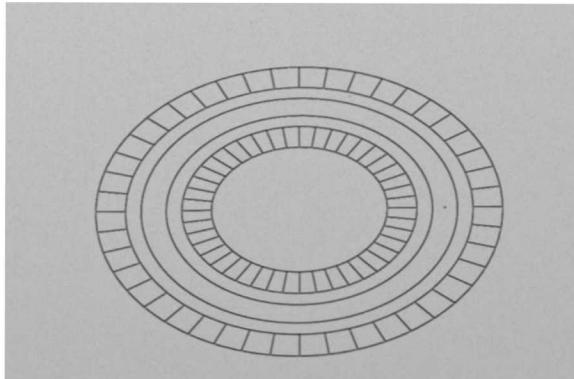
## Derived requirements

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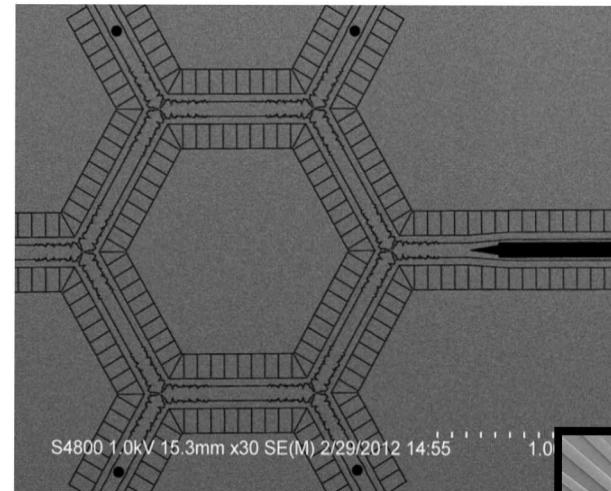


# Unique Traps From Sandia

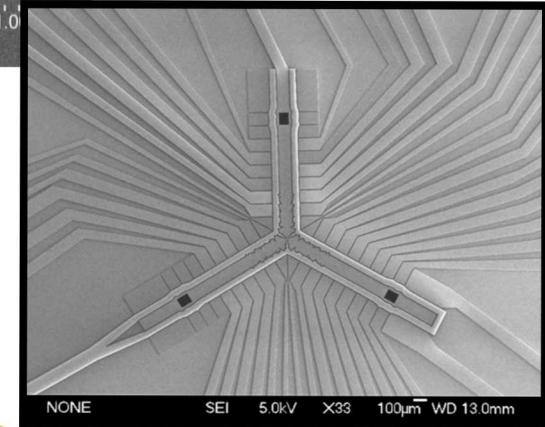


**Ring trap**

Tabakov, B et al. *Phys. Rev. Applied* **4**, 031001 (2015).

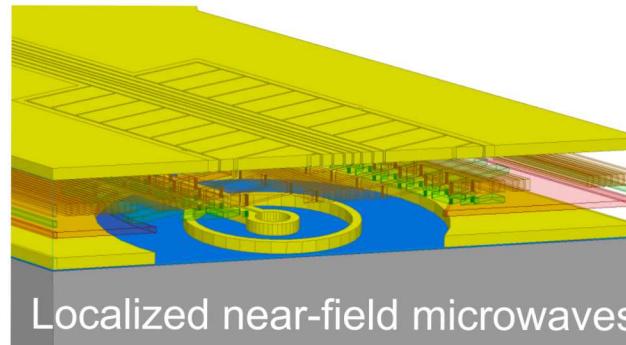


**Circulator Trap**



**Y-junction trap**

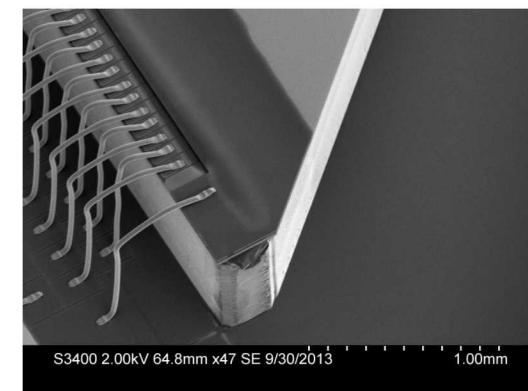
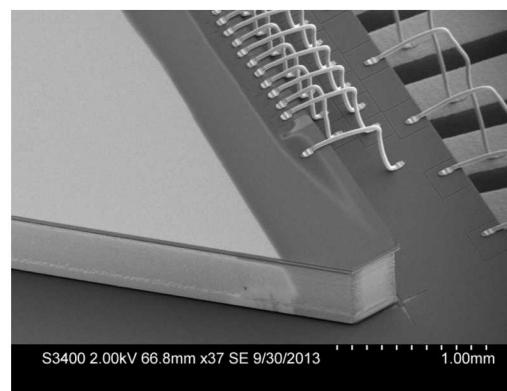
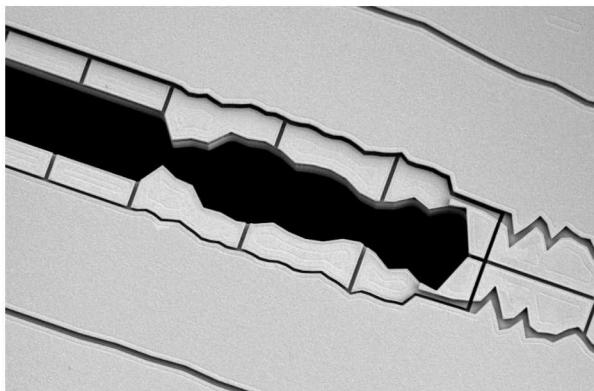
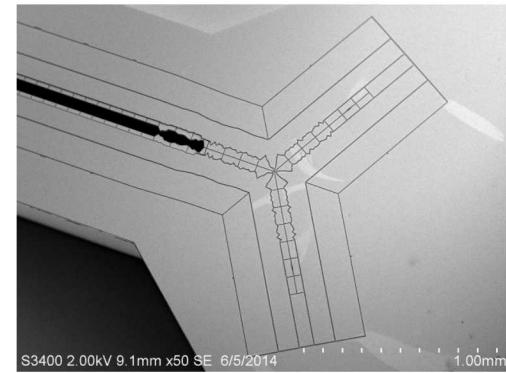
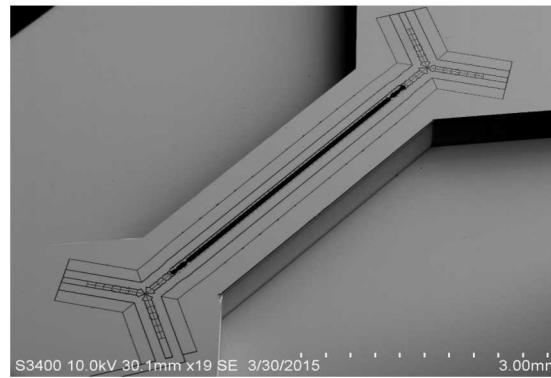
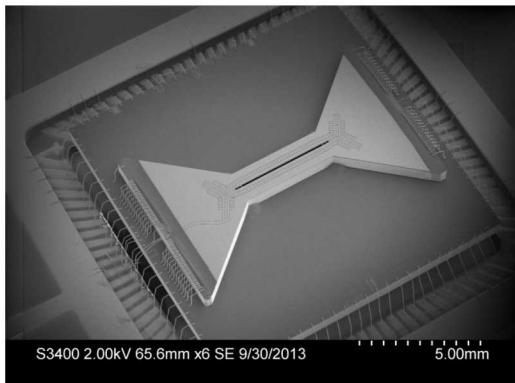
**Microwave trap**



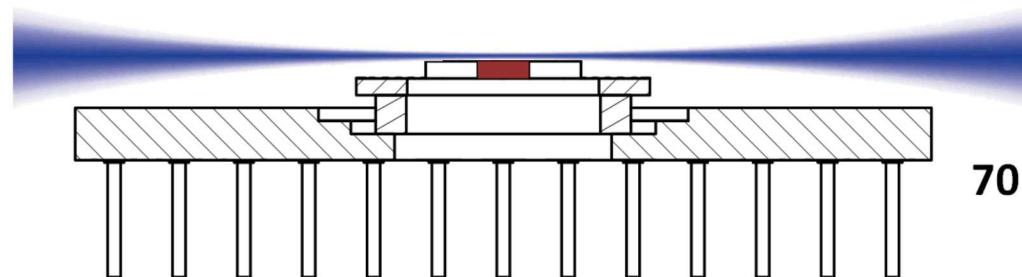
**Localized near-field microwaves**

330 ns  $\pi$ -time,  $10^{-5}$  single qubit gate errors

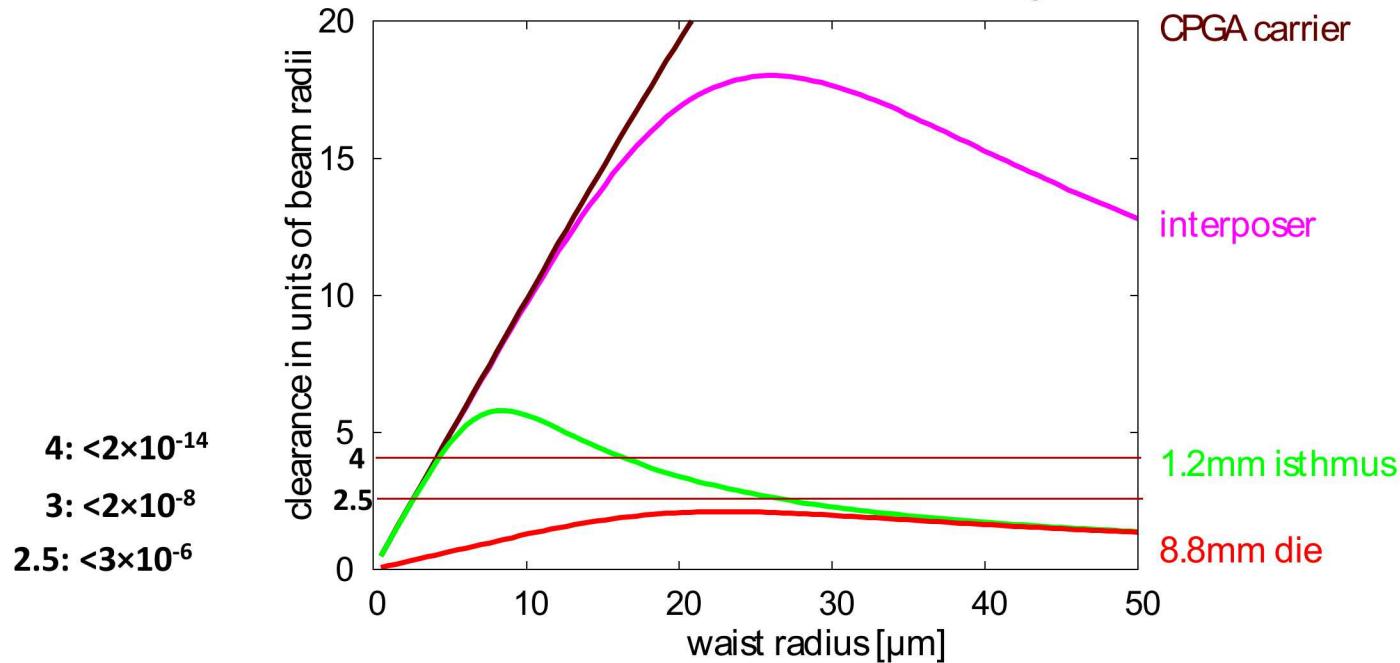
# High Optical Access (HOA)



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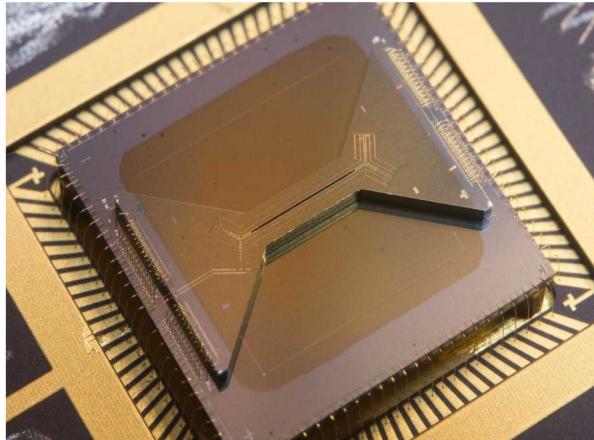
clearance for a surface skimming beam



4:  $<2 \times 10^{-14}$   
3:  $<2 \times 10^{-8}$   
2.5:  $<3 \times 10^{-6}$

4  $\mu\text{m}$  waist is possible

# High Optical Access (HOA)

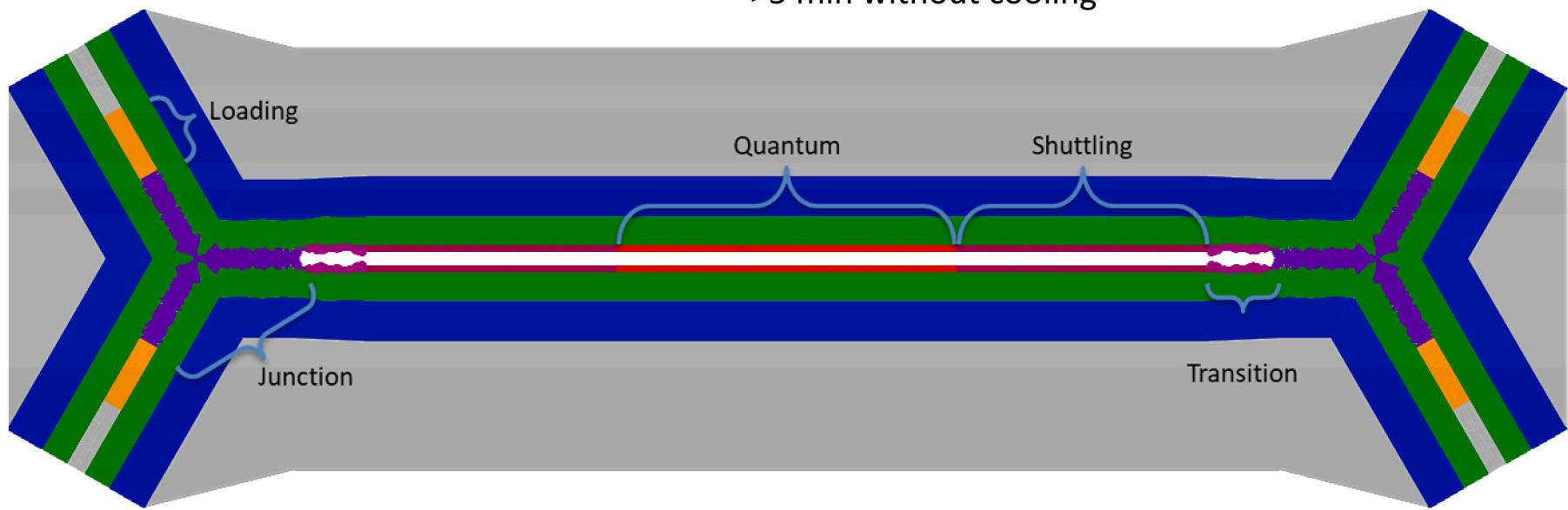


## Optical access

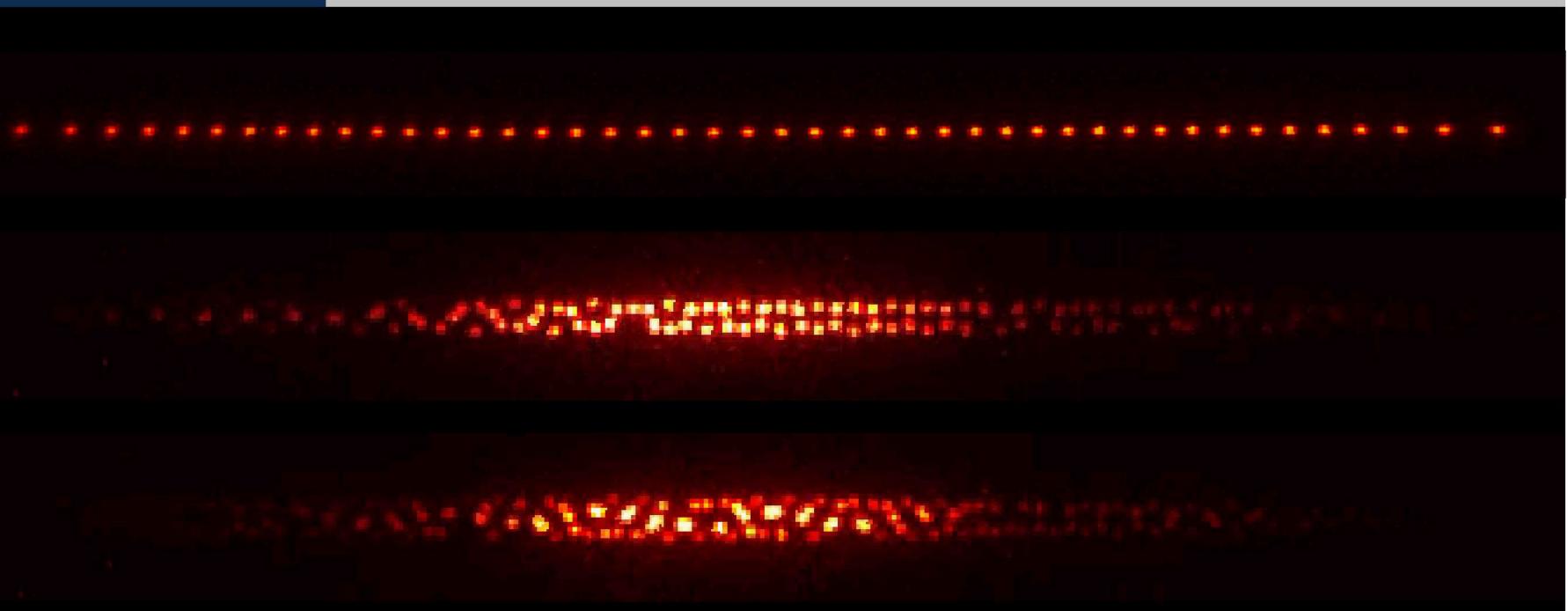
- Excellent optical access rivaling 3-D

## Trap strength (Typical Yb<sup>+</sup>)

- Radial trap frequency 2 - 5 MHz
- RF frequency 50 MHz
- Stable for long ion chains
- Low heating rates (30 q/s parallel to surface, 125 q/s perpendicular)
- >100 h observed (while running measurements)
- >5 min without cooling



# Trapped ion chains



- Observed storage times between
  - 16 min for long linear chain
  - 16 h for 3d crystal
- Most likely limited by background collisions
- Property of vacuum conditions
- Losing all ions at once (one might come back)

# Electric Field Control

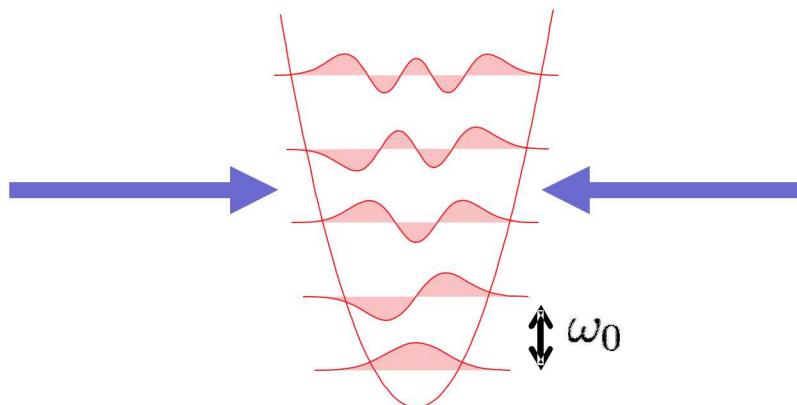
When ions are trapped, they exhibit vibrational modes the trapping directions.

**Secular Frequency:** One for each trapping direction

**The motional modes are important:**

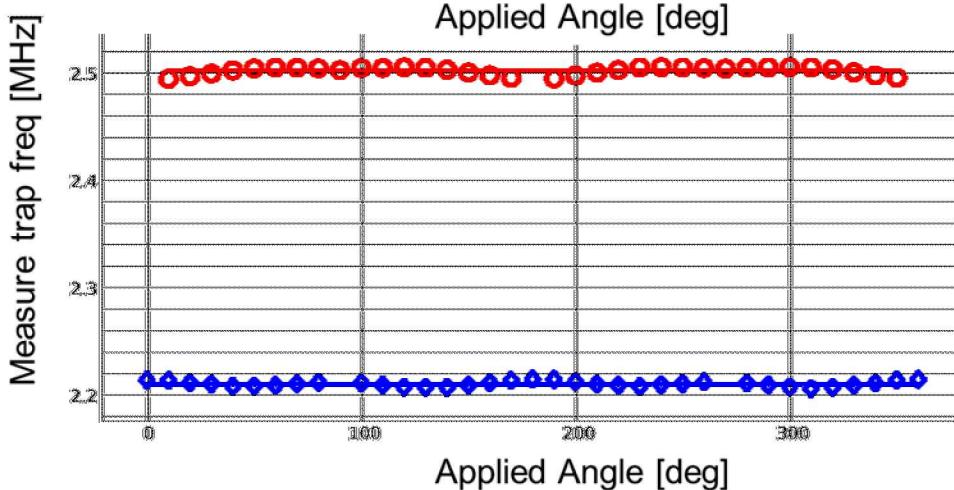
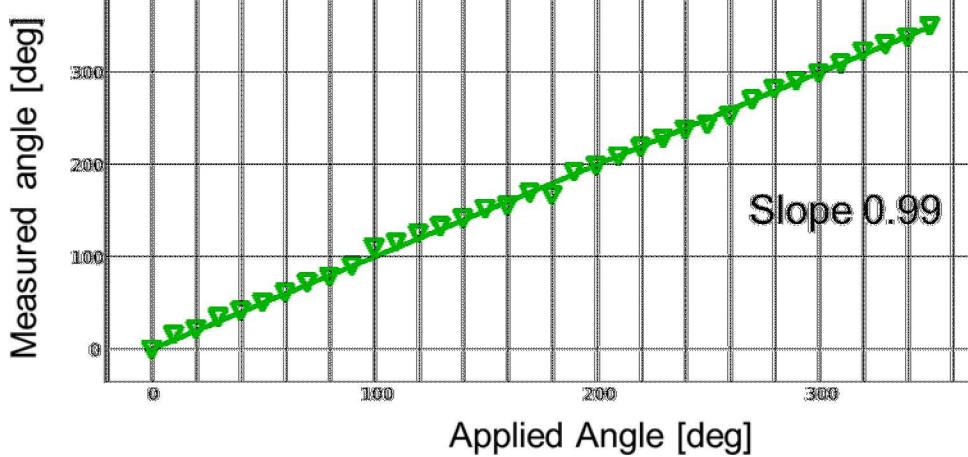
- Interactions between ions
- Allow for cooling to the ground state
- Dictate sensitivity to noise sources

The frequency of the modes are controlled by the strength of the trap



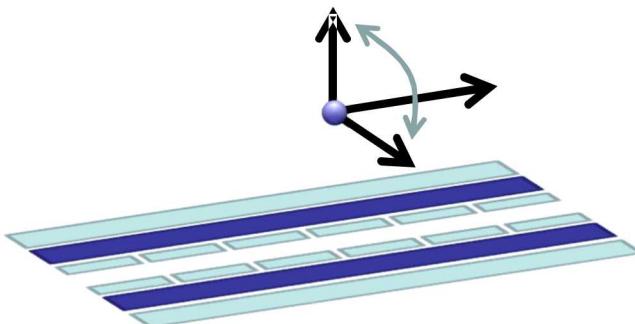
Stronger fields have the effect of a narrowing the well, and thus larger secular frequencies

# Electric Field Modeling from Trap Design is Accurate

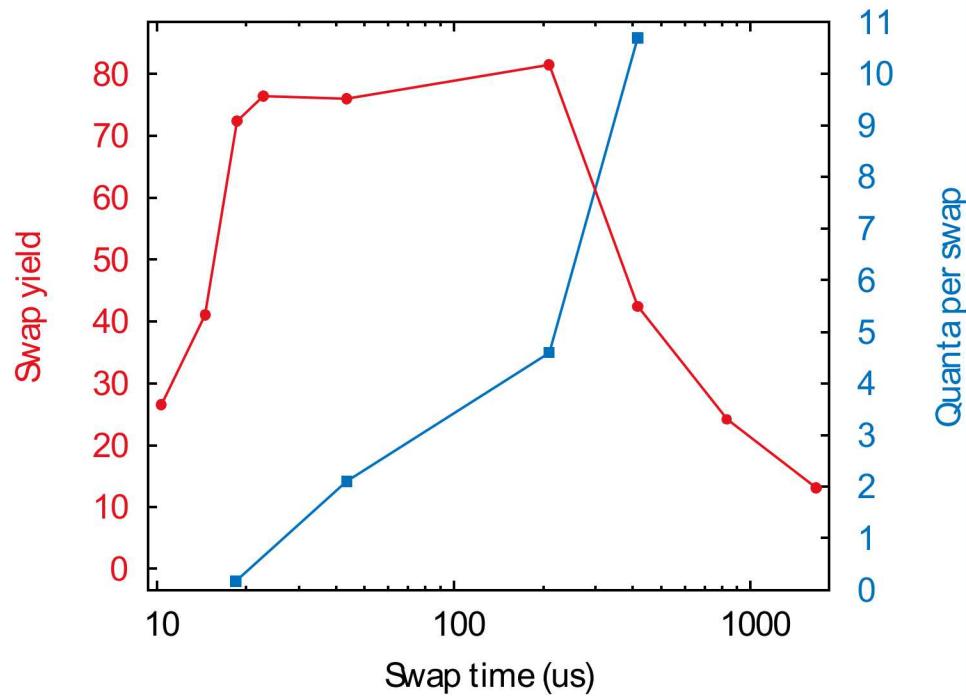
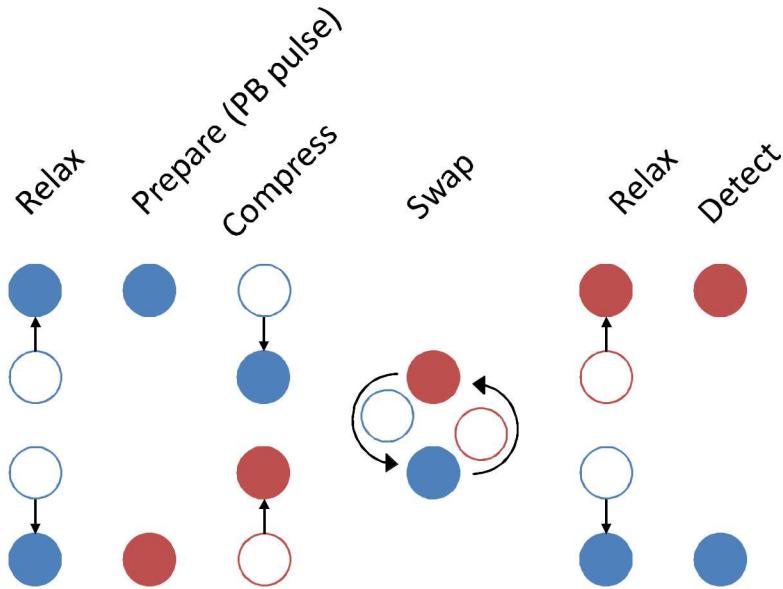


## Electric field control

- Do we understand the trapping fields?
- Principal axes rotation realized as in simulation
- No change in trap frequencies
- The simulations accurately describe the fields and curvatures generated by the trap



# Electric Field Control from Surface Traps: Swapping ions



## Advantages of parametric trapping solutions:

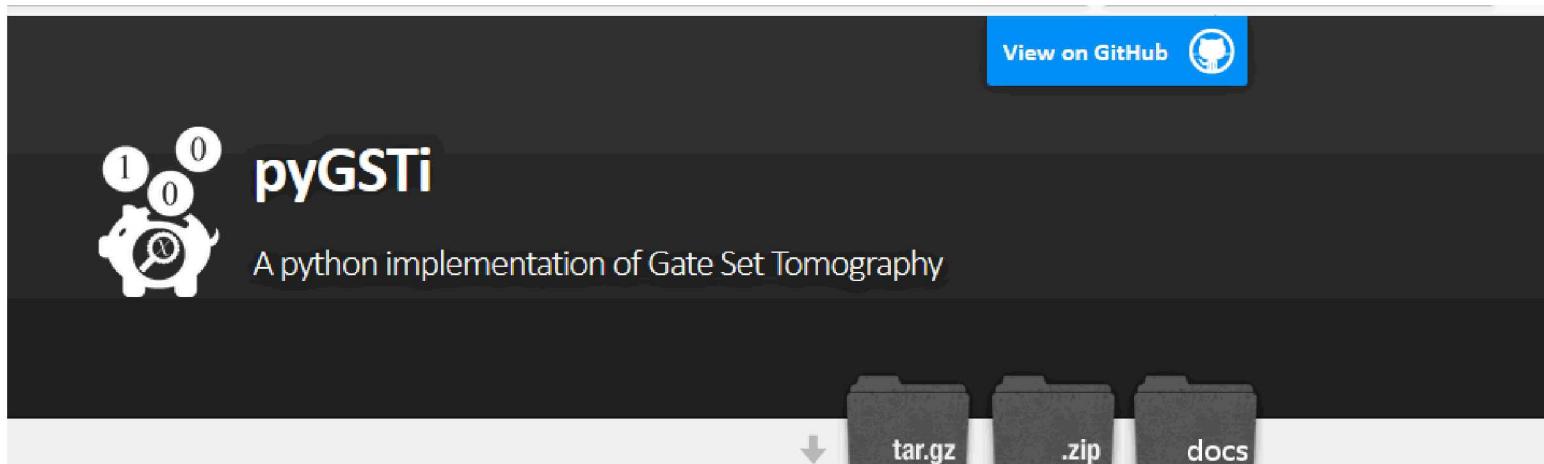
- Primitives in terms of curvature tensor elements and can be applied at any location in the trap.
- Shuttling primitives can be easily combined
- Example: rotating ion crystal while translating through the trap

# Testing High Fidelity Operations with GST

Gate Set Tomography, developed at Sandia  
Robin Blume-Kohout, Erik Nielsen, et al.

<http://www.pygsti.info/>

Available on GitHub: <https://github.com/pyGSTi/pyGSTi>



## Getting Started

**pyGSTi** is a software package to perform gate set tomography (GST). GST is a kind of quantum tomography, and it provides full characterization of quantum logic gates on quantum devices such as qubits. For a basic (albeit out of date) introduction to GST, see <http://arxiv.org/abs/1605.07674> (by the pyGSTi authors) or <http://arxiv.org/abs/1509.02921> (by an independent 3rd party). The first of these papers describes a relatively recent use of GST, similar to what's in pyGSTi. The second describes a more primitive initial version of gate set tomography which looks much different than the current pyGSTi code. More recently, the appendix of <https://www.nature.com/articles/ncomms14485> contains descriptions of GST's major components.

# How Gate Set Tomography (GST) Works

Start with a few gates that you want to test:

X:  $\pi/2$  rotation about x-axis

Y:  $\pi/2$  rotation about y-axis

i: idle gate (do nothing)

GST uses those gates to form “**germs**” which are small sets of these primitive gates

X, Y, i, XY, XYi, XiY, Xii, Yii, XXiY, XYYi, XXYYXY

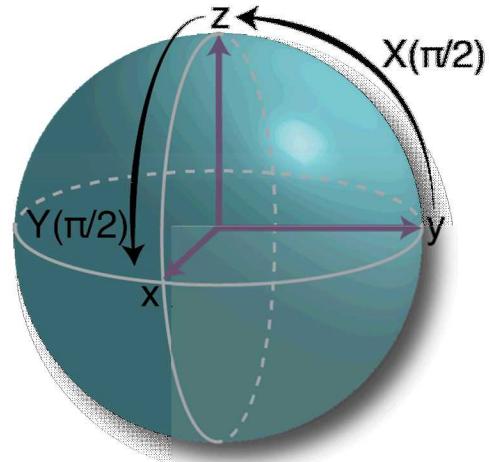
GST uses a small set of “**fiducials**” made of the primitives for preparation and measurement (six orthogonal poles)

{}, X, Y, XX, XXX, YYY

Using combinations of

**fiducial1 – (germ)<sup>n</sup> – fiducial2**

To make strings of gates that are applied to the system



**GST is:**

- Self Consistent** (fiducials are not assumed perfect)
- Efficient** (repeating germs amplifies the errors)
- Sensitive** (germs chosen to be sensitive to all types of errors)

# Information that GST Reports

The screenshot shows the GST software interface. The sidebar on the left contains the following sections and their sub-options:

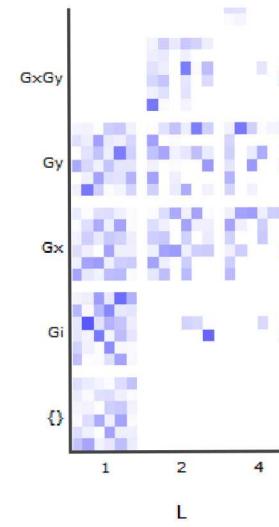
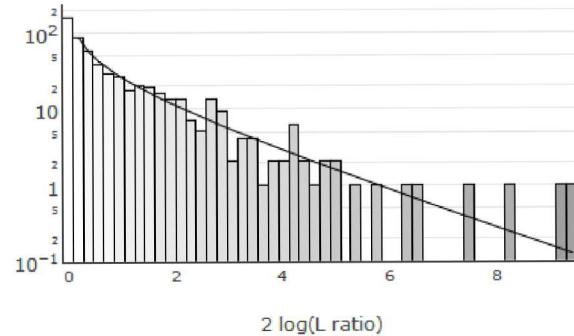
- Summary**
- Model Violation**
  - Overview
  - Per-sequence detail
  - Robust data scaling
- Gauge Invariant Error Metrics**
  - Overview
  - Germs Detail
- Gauge Dependent Error Metrics**
  - Overview
  - Raw Estimates
  - Gate Decompositions
  - Gate Error Generators**
- For Reference**
  - Input Reference
  - System Reference
- Help**
- Estimate**
  - CPTP.Robust+
- C-Opt Param**

C-Opt Param	Value
0: Item weights	gates=1, spam=0
0: Gauge group	Unitary
1: SPAM penalty factor	1.0
1: Item weights	gates=0, spam=1
1: Gauge group	TP Spam

Many different ways to report fidelity  
Ask your theorist which is preferred!  
GST gives you all of these:

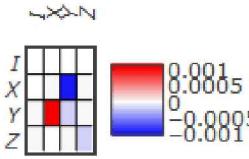
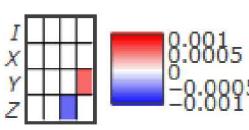
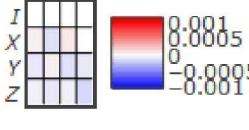
- Entanglement Infidelity
- Average Gate Infidelity
- Non-Unitary Entanglement Infidelity
- Non-Unitary Average Gate Infidelity
- $\frac{1}{2}$  Diamond-Distance
- $\frac{1}{2}$  Non-Unitary Diamond-Distance
- Randomized Benchmarking Number
- Eigenvalues and Matrices
- Gate Decompositions
- Gate Error Generators
- Estimated Rotation Angles
- Rotation Angles between Gates

Along with visuals to more quickly detect patterns of errors



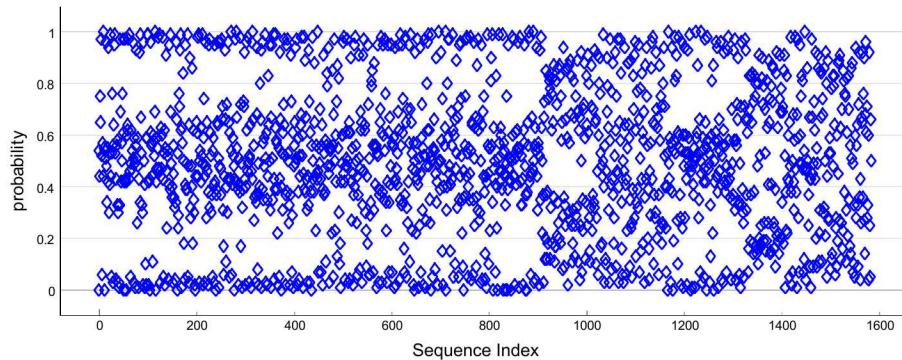
# Information that GST Reports

## Different Types of Error Generators

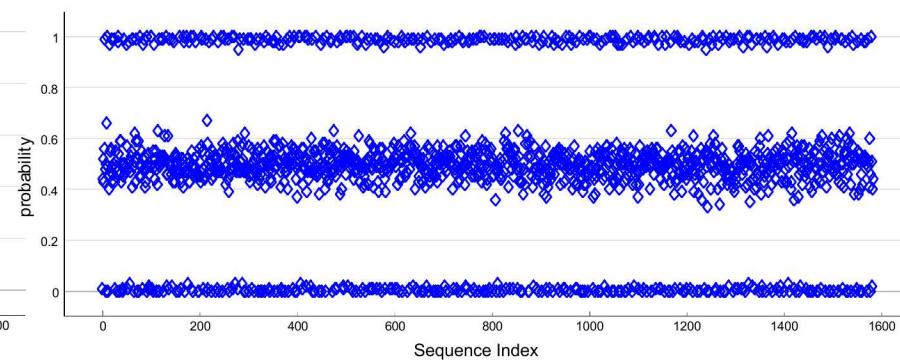
Gate	Error Generator	Pauli Hamiltonian Projections	Pauli Stochastic Projections	Pauli Affine Projections																													
Gi	 <p>Power 0.96</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>1m5</td><td>5m6</td><td>5m4</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	1m5	5m6	5m4		<p>Power 0.032</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>-1m4</td><td>9m5</td><td>9m6</td><td>1m6</td><td></td> </tr> </table>	Q1	I	X	Y	Z	-1m4	9m5	9m6	1m6		<p>Power 0.00075</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>1m5</td><td>-2m5</td><td>-3m5</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	1m5	-2m5	-3m5	
Q1	I	X	Y	Z																													
0	1m5	5m6	5m4																														
Q1	I	X	Y	Z																													
-1m4	9m5	9m6	1m6																														
Q1	I	X	Y	Z																													
0	1m5	-2m5	-3m5																														
Gx	 <p>Power 1</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>-3m4</td><td>4m6</td><td>4m6</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	-3m4	4m6	4m6		<p>Power 0.00011</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>-4m6</td><td>4m7</td><td>2m6</td><td>2m6</td><td></td> </tr> </table>	Q1	I	X	Y	Z	-4m6	4m7	2m6	2m6		<p>Power 6.1e-05</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>6m6</td><td>-2m6</td><td>-2m6</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	6m6	-2m6	-2m6	
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0	-3m4	4m6	4m6																														
Q1	I	X	Y	Z																													
-4m6	4m7	2m6	2m6																														
Q1	I	X	Y	Z																													
0	6m6	-2m6	-2m6																														
Gy	 <p>Power 0.041</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>4m6</td><td>2m5</td><td>-4m6</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	4m6	2m5	-4m6		<p>Power 0.59</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>-1m4</td><td>3m5</td><td>3m5</td><td>3m5</td><td></td> </tr> </table>	Q1	I	X	Y	Z	-1m4	3m5	3m5	3m5		<p>Power 0.15</p> <table border="1"> <tr> <td>Q1</td> <td>I</td><td>X</td><td>Y</td><td>Z</td> </tr> <tr> <td>0</td><td>4m5</td><td>-9m5</td><td>-6m5</td><td></td> </tr> </table>	Q1	I	X	Y	Z	0	4m5	-9m5	-6m5	
Q1	I	X	Y	Z																													
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-1m4	3m5	3m5	3m5																														
Q1	I	X	Y	Z																													
0	4m5	-9m5	-6m5																														

# GST – Microwaves (horn)

Raw data poor gates

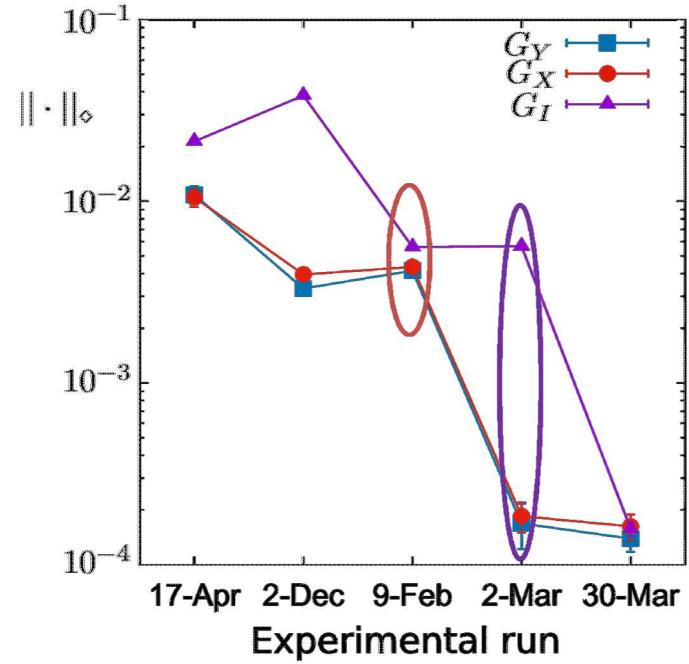


Raw data good gates



Gate	Rotn. axis	Angle
$G_I$	0.5252	
	-0.009	
	0.8506	
	-0.0244	$0.001699\pi$
$G_X$	$-3 \times 10^{-6}$	
	-1	
	$-3 \times 10^{-5}$	
	-0.009	$0.501308\pi$
$G_Y$	-0.2474	
	0.0001	
	0.9689	
	-0.0001	$0.501366\pi$

Gate	Rotn. axis	Angle
$G_I$	-0.0035	
	0.014	
	-0.9999	
	0.0006	$0.001769\pi$
$G_X$	$-3 \times 10^{-5}$	
	-1	
	$1 \times 10^{-4}$	
	0.0006	$0.500007\pi$
$G_Y$	0.1104	
	$4 \times 10^{-5}$	
	0.9939	
	0.0005	$0.50001\pi$



# Microwave Gates using Microwave Trap (Single Qubit)

## GST Results

Gate	Gi	Gx	Gy
Ent. Infidelity	$1.4 \times 10^{-5}$	$3.5 \times 10^{-5}$	$2.1 \times 10^{-5}$
Avg. Gate Infidelity	$9.2 \times 10^{-6}$	$2.3 \times 10^{-5}$	$1.4 \times 10^{-5}$
Non-U. Ent. Infidelity	$1.4 \times 10^{-5}$	$3.5 \times 10^{-5}$	$2.1 \times 10^{-5}$
Non U. Avg. Gate Infidelity	$9.2 \times 10^{-6}$	$2.3 \times 10^{-5}$	$1.4 \times 10^{-5}$
$\frac{1}{2}$ Diamond-Dist.	$6.5 \times 10^{-4}$	$2.4 \times 10^{-4}$	$1.3 \times 10^{-4}$
$\frac{1}{2}$ Non-U. Diamond-Dist	$1.4 \times 10^{-5}$	$3.9 \times 10^{-5}$	$2.3 \times 10^{-5}$

Entanglement Infidelity  $< 3.5 \times 10^{-5}$   
 $\frac{1}{2}$  diamond norm  $< 6.5 \times 10^{-4}$

} Indicates Systematic  
Error

# Laser based Raman gates



- co-propagating beam geometry
  - Motion independent
  - No optical phase imprinted

- BB1 dynamically compensated pulse sequences

## GST results:

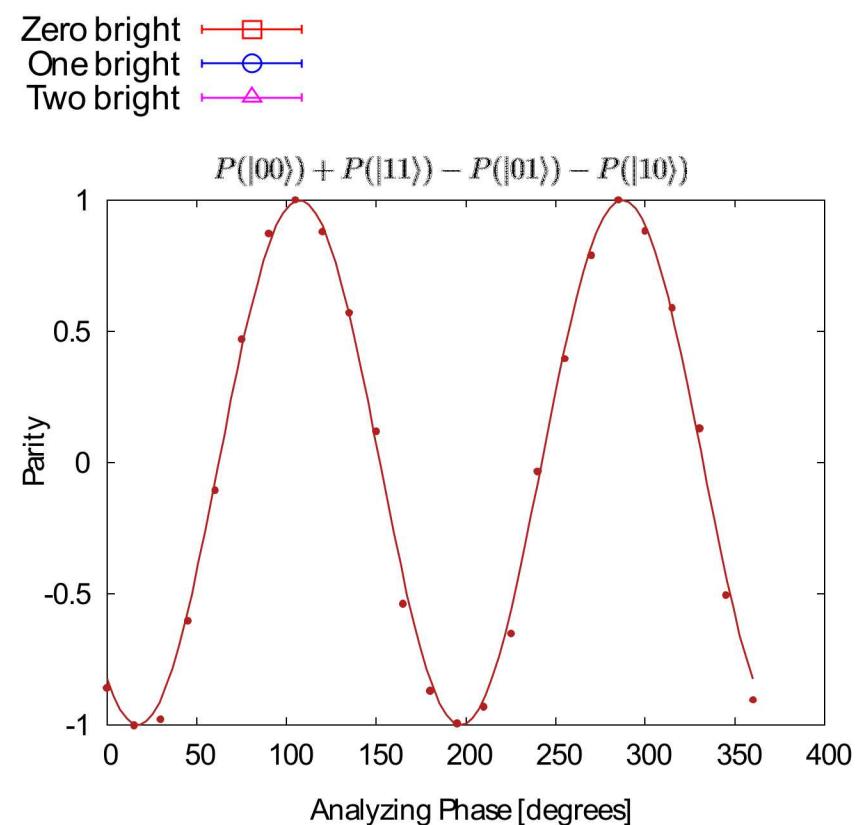
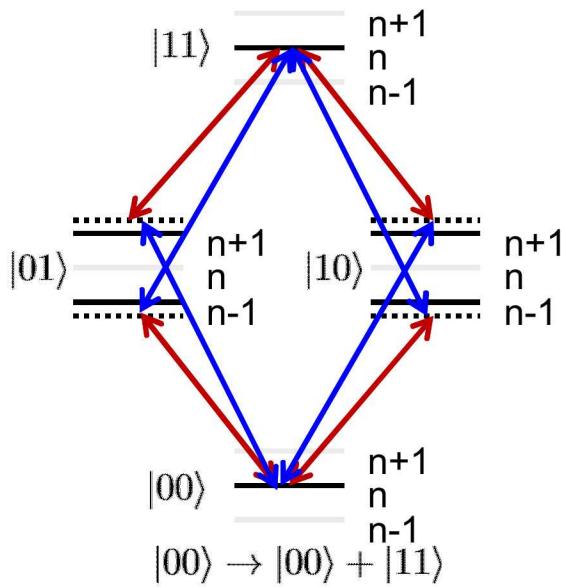
95% confidence intervals

	Conventional pulses		Gapless pulses	
Gate	Process Infidelity	$1/2 \diamond$ -Norm	Process Infidelity	$1/2 \diamond$ -Norm
$G_I$	$0.05(2) \times 10^{-4}$	$12(1) \times 10^{-4}$	$1.1(1) \times 10^{-4}$	$5.3(2) \times 10^{-4}$
$G_X$	$1.3(1) \times 10^{-4}$	$4(2) \times 10^{-4}$	$0.5(1) \times 10^{-4}$	$2(6) \times 10^{-4}$
$G_Y$	$1.6(4) \times 10^{-4}$	$4(3) \times 10^{-4}$	$0.7(1) \times 10^{-4}$	$4(9) \times 10^{-4}$

Quantum optics and lasers  
Quantum optics and lasers

## Mølmer-Sørensen gates

- Mølmer-Sørensen gates [1]
- All two-qubit gates implemented using Walsh compensation pulses [2]

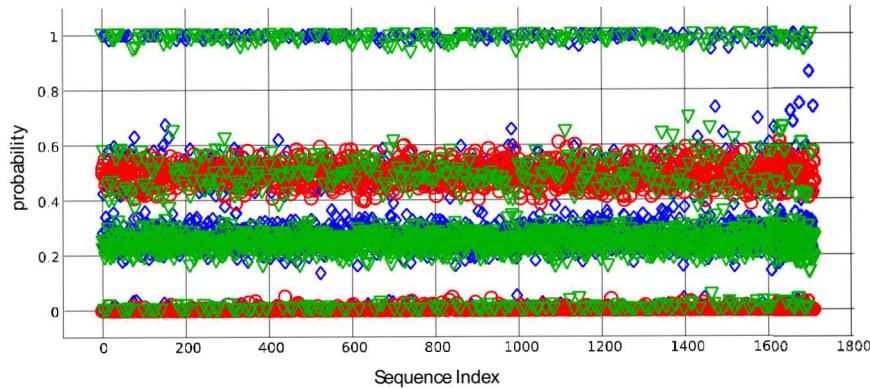


$$\mathcal{F} = \frac{1}{2}(P(|00\rangle) + P(|11\rangle)) + \frac{1}{4}c \approx 0.995$$

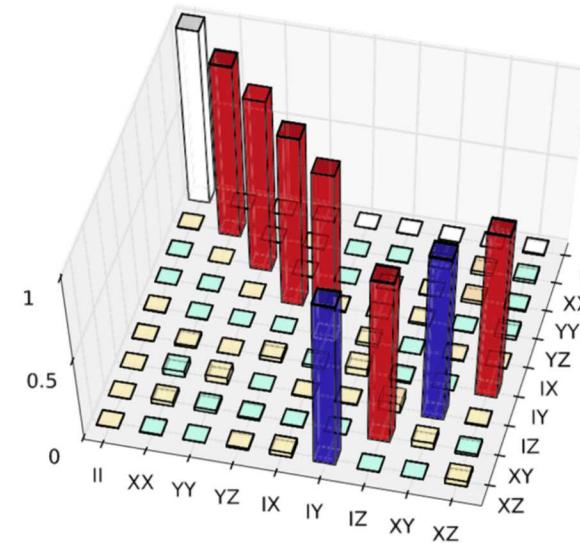
[1] K. Mølmer, A. Sørensen, PRL 82, 1835 (1999)

[2] D. Hayes et al. Phys. Rev. Lett. 109, 020503 (2012)

## GST on symmetric subspace



Zero ions bright  
 One ion bright  
 Two ions bright



Gate	Process infidelity	$\frac{1}{2}$ Diamond norm
$G_I$	$1.6 \times 10^{-3} \pm 1.6 \times 10^{-3}$	$28 \times 10^{-3} \pm 7 \times 10^{-3}$
$G_{XX}$	$0.4 \times 10^{-3} \pm 1.0 \times 10^{-3}$	$27 \times 10^{-3} \pm 5 \times 10^{-3}$
$G_{YY}$	$0.1 \times 10^{-3} \pm 0.9 \times 10^{-3}$	$26 \times 10^{-3} \pm 4 \times 10^{-3}$
$G_{MS}$	$4.2 \times 10^{-3} \pm 0.6 \times 10^{-3}$	$38 \times 10^{-3} \pm 5 \times 10^{-3}$

95% confidence intervals

Process fidelity of two-qubit Mølmer-Sørensen gate > 99.5%

# Summary

## Surface Traps fabricated at Sandia demonstrate a many building blocks for larger systems: Good Platform for Future

- Ion shuttling and position control
- High fidelity quantum operations

## Leveraging DOE facilities

- MESA facility – capabilities align well with trap requirements
  - Engineers and technologists essential to fabricating and packaging the many traps needed at SNL and academic/commercial partners
- Engineering and simulations
  - Microwave design
  - Quantum theory – tomography and error correction

## Future research

- Next Slide!



# Future Work with Ions at Sandia

Department of Energy

## Department of Energy Announces \$218 Million for Quantum Information Science

SEPTEMBER 24, 2018

[Home](#) » Department of Energy Announces \$218 Million for Quantum Information Science

### Field Will Shape Future of Information Processing

WASHINGTON, D.C. – Today, the U.S. Department of Energy (DOE) announced \$218 million in funding for 85 research awards in the important emerging field of Quantum Information Science (QIS). The awards were made in conjunction with the White House Summit on Advancing American Leadership in QIS, highlighting the high priority that the Administration places on advancing this multidisciplinary area of research, which is expected to lay the foundation for the next generation of computing and information processing as well as an array of other innovative technologies.

# Future Work with Ions at Sandia

**QSCOUT**: DOE funded, goal of making a stable, public platform (testbed) from trapped ions for the scientific community to perform experiments

**LogiQ**: IARPA funded, goal of making a logical qubit with errors rates less than the physical qubits that compose it

[www.sandia.gov](http://www.sandia.gov) → Careers → View All Jobs

Postdoctoral Appointee – AMO Physics Job ID 663692  
Ion Trapping  
Peter Maunz ([plmaunz@sandia.gov](mailto:plmaunz@sandia.gov))

Postdoctoral Appointee – AMO Physics Job ID 663398  
Atomic Sensing and Clocks  
Peter Schwint ([pschwin@sandia.gov](mailto:pschwin@sandia.gov))

Two-qubit gates in Rydberg atoms, atom interferometers  
Grant Biedermann ([gbeider@sandia.gov](mailto:gbeider@sandia.gov))

# Summary

## Surface Traps fabricated at Sandia demonstrate many building blocks for larger systems:

- Ion shuttling and position control
- High fidelity quantum operations
- Beginning sympathetic cooling

## Leveraging DOE facilities

- MESA facility – capabilities align well with trap requirements
  - Engineers and technologists essential to fabricating and packaging the many traps needed at SNL and academic/commercial partners
- Engineering and simulations
  - Microwave design
  - Quantum theory – tomography and error correction

## Future research

- DOE testbed
- LogiQ research

### *Trap design and fabrication*

Matthew Blain  
Ed Heller  
Corrie Herrmann  
Becky Loviza  
John Rembetski  
Paul Resnick  
MESA team

### *Trap packaging*

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Drew Hollowell  
Anathea Ortega  
Tipp Jennings

### *GST protocols*

Robin Blume-Kohout  
Kenneth Rudinger  
Eric Nielsen

### *Trap design and experimental work*

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